


<b>Search Notes</b>  	<b>Application/Control No.</b>  09265073	<b>Applicant(s)/Patent Under Reexamination</b>  OVARD ET AL.
	<b>Examiner</b>  Nam V Nguyen	<b>Art Unit</b>  2612

SEARCHED			
Class	Subclass	Date	Examiner
340	10.4;	7/5/08	NN
455	38.2; 106; 73	7/5/08	NN

SEARCH NOTES		
Search Notes	Date	Examiner
Search EAST: uspat; us-pub; epo; jpo and derwent (updated search).	7/5/08	NN
Search Terms: interrogation with plurality of stations; rf circuitry for different ranges.	7/5/08	NN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner